

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		09/876,183	CHANG ET AL.	
Examiner		Art Unit		Page 1 of 1
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-6,727,735	04-2004	Park, Kwang-II	327/157
X	B	US-6,577,694	06-2003	Meghelli, Mounir	375/373
X	C	US-6,473,439	10-2002	Zerbe et al.	370/503
X	D	US-6,373,293	04-2002	Best, Scott C.	327/2
X	E	US-6,279,063	08-2001	Kawasaki et al.	710/110
X	F	US-6,081,572	06-2000	Filip, Jan	375/376
X	G	US-5,966,033	10-1999	Miller, Charles A.	327/3
X	H	US-5,923,190	07-1999	Yamaguchi, Junichiro	327/12
X	I	US-5,825,209	10-1998	Stark et al.	327/3
X	J	US-5,663,685	09-1997	Kesner, Donald R.	331/1A
X	K	US-5,614,855	03-1997	Lee et al.	327/158
X	L	US-5,072,195	12-1991	Graham et al.	331/2
X	M	US-4,712,060	12-1987	Bailey et al.	324/76.77

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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